
PART NUMBER**74ACTQ16543MTD-G-ROCV**

Rochester Electronics**Manufactured Components**

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

- Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

74ACTQ16543

16-Bit Registered Transceiver with 3-STATE Outputs

General Description

The ACTQ16543 contains sixteen non-inverting transceivers containing two sets of D-type registers for temporary storage of data flowing in either direction. Each byte has separate control inputs which can be shorted together for full 16-bit operation. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent input and output control in either direction of data flow.

The ACTQ16543 utilizes Fairchild Quiet Series™ technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector for superior performance.

Features

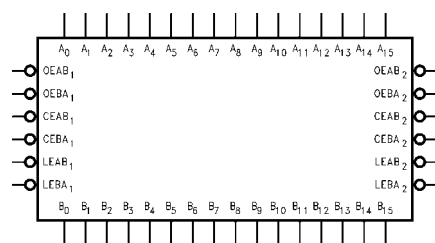
- Utilizes Fairchild FACT Quiet Series technology
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin output skew
- Independent registers for A and B buses
- Separate controls for data flow in each direction
- Back-to-back registers for storage
- Multiplexed real-time and stored data transfers
- Separate control logic for each byte
- 16-bit version of the ACTQ543
- Outputs source/sink 24 mA
- Additional specs for Multiple Output Switching
- Output loading specs for both 50 pF and 250pF loads

Ordering Code:

| Order Number | Package Number | Package Description |
|----------------|----------------|---|
| 74ACTQ16543SSC | MS56A | 56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300" Wide |
| 74ACTQ16543MTD | MTD56 | 56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide |

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbol



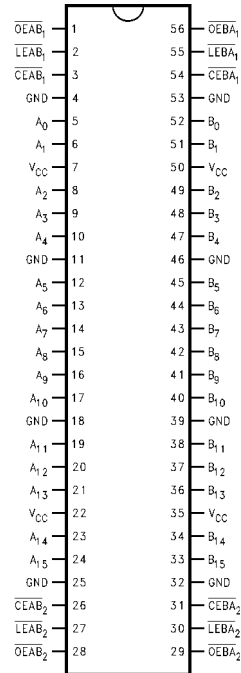
Pin Descriptions

| Pin Names | Descriptions |
|---------------------------------|---|
| OEAB _n | A-to-B Output Enable Input (Active LOW) |
| OEBA _n | B-to-A Output Enable Input (Active LOW) |
| CEAB _n | A-to-B Enable Input (Active LOW) |
| CEBA _n | B-to-A Enable Input (Active LOW) |
| LEAB _n | A-to-B Latch Enable Input (Active LOW) |
| LEBA _n | B-to-A Latch Enable Input (Active LOW) |
| A ₀ -A ₁₅ | A-to-B Data Inputs or B-to-A 3-STATE Outputs |
| B ₀ -B ₁₅ | B-to-A Data Inputs or A-to-B 3-STATE Outputs |

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Connection Diagram

Pin Assignment for SSOP and TSSOP



Functional Description

The ACTQ16543 contains sixteen non-inverting transceivers with 3-STATE outputs. The device is byte controlled with each byte functioning identically, but independent of the other. The control pins may be shorted together to obtain full 16-bit operation. The following description applies to each byte. For data flow from A to B, for example, the A-to-B Enable (\overline{CEAB}_n) input must be LOW in order to enter data from A_0 – A_{15} or take data from B_0 – B_{15} , as indicated in the Data I/O Control Table. With \overline{CEAB}_n LOW, a LOW signal on the A-to-B Latch Enable (\overline{LEAB}_n) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the \overline{LEAB}_n signal puts the A latches in the storage mode and their outputs no longer change with the A inputs. With \overline{CEAB}_n and \overline{OEAB}_n both LOW, the 3-STATE B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is similar, but using the \overline{CEBA}_n , \overline{LEBA}_n and \overline{OEBA}_n inputs.

Data I/O Control Table

| Inputs | | | Latch Status (Byte n) | Output Buffers (Byte n) |
|---------------------|---------------------|---------------------|--------------------------|-------------------------------|
| \overline{CEAB}_n | \overline{LEAB}_n | \overline{OEAB}_n | | |
| H | X | X | Latched | High Z |
| X | H | X | Latched | — |
| L | L | X | Transparent | — |
| X | X | H | — | High Z |
| L | X | L | — | Driving |

H = HIGH Voltage Level

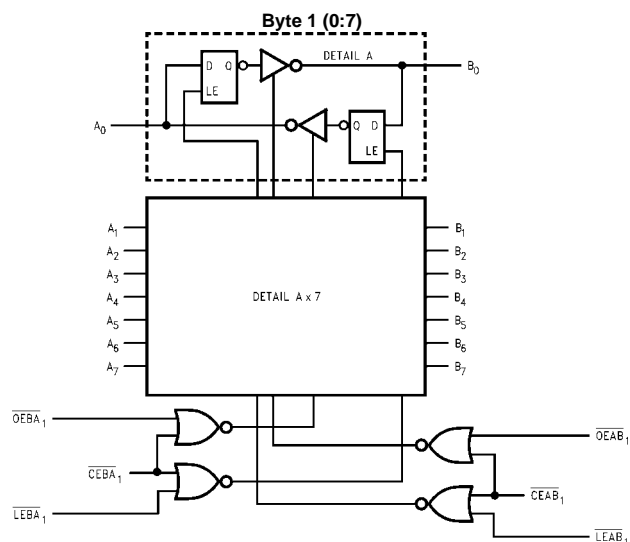
L = LOW Voltage Level

X = Immaterial

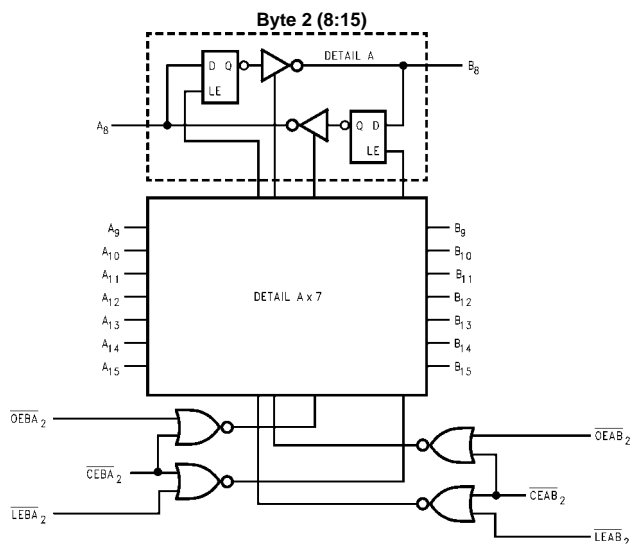
A-to-B data flow shown; B-to-A flow control

is the same, except using \overline{CEBA}_n , \overline{LEBA}_n and \overline{OEBA}_n

Logic Diagrams



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

| | |
|---|--------------------------|
| Supply Voltage (V_{CC}) | -0.5V to +7.0V |
| DC Input Diode Current (I_{IK}) | |
| $V_I = -0.5V$ | -20 mA |
| $V_I = V_{CC} + 0.5V$ | +20 mA |
| DC Output Diode Current (I_{OK}) | |
| $V_O = -0.5V$ | -20 mA |
| $V_O = V_{CC} + 0.5V$ | +20 mA |
| DC Output Voltage (V_O) | -0.5V to $V_{CC} + 0.5V$ |
| DC Output Source/Sink Current (I_O) | ±50 mA |
| DC V_{CC} or Ground Current | |
| per Output Pin | ±50 mA |
| Storage Temperature | -65°C to +150°C |

Recommended Operating Conditions

| | |
|---|----------------|
| Supply Voltage (V_{CC}) | 4.5V to 5.5V |
| Input Voltage (V_I) | 0V to V_{CC} |
| Output Voltage (V_O) | 0V to V_{CC} |
| Operating Temperature (T_A) | -40°C to +85°C |
| Minimum Input Edge Rate ($\Delta V/\Delta t$) | 125 mV/ns |
| V_{IN} from 0.8V to 2.0V | |
| V_{CC} @ 4.5V, 5.5V | |

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics

| Symbol | Parameter | V _{CC} (V) | T _A = +25°C | | T _A = −40°C to+85°C | Units | Conditions |
|------------------|--|------------------------|------------------------|-----------------------|--------------------------------|-------|--|
| | | | Typ | Guaranteed Limits | | | |
| V _{IH} | Minimum HIGH Input Voltage | 4.5 | 1.5 | 2.0 | 2.0 | V | V _{OUT} = 0.1V |
| | | 5.5 | 1.5 | 2.0 | 2.0 | | or V _{CC} − 0.1V |
| V _{IL} | Maximum LOW Input Voltage | 4.5 | 1.5 | 0.8 | 0.8 | V | V _{OUT} = 0.1V |
| | | 5.5 | 1.5 | 0.8 | 0.8 | | or V _{CC} − 0.1V |
| V _{OH} | Minimum HIGH Output Voltage | 4.5 | 4.49 | 4.4 | 4.4 | V | I _{OUT} = −50 μA |
| | | 5.5 | 5.49 | 5.4 | 5.4 | | |
| | | 4.5 | | 3.86 | 3.76 | V | V _{IN} = V _{IL} or V _{IH} |
| | | 5.5 | | 4.86 | 4.76 | | I _{OH} = −24 mA |
| V _{OL} | Maximum LOW Output Voltage | 4.5 | 0.001 | 0.1 | 0.1 | V | I _{OH} = −24 mA (Note 2) |
| | | 5.5 | 0.001 | 0.1 | 0.1 | | I _{OUT} = 50 μA |
| | | 4.5 | | 0.36 | 0.44 | V | V _{IN} = V _{IL} or V _{IH} |
| | | 5.5 | | 0.36 | 0.44 | | I _{OL} = 24 mA |
| I _{OZT} | Maximum I/O Leakage Current | 5.5 | | ±0.5 | ±5.0 | μA | I _{OL} = 24 mA (Note 2) |
| I _{IN} | Maximum Input Leakage Current | 5.5 | | ±0.1 | ±1.0 | μA | V _I = V _{IL} , V _{IH} V _O = V _{CC} , GND |
| I _{CCT} | Maximum I _{CC} /Input | 5.5 | 0.6 | | 1.5 | mA | V _I = V _{CC} − 2.1V |
| I _{CC} | Max Quiescent Supply Current | 5.5 | | 8.0 | 80.0 | μA | V _{IN} = V _{CC} or GND |
| I _{OLD} | Minimum Dynamic | 5.5 | | | 75 | mA | V _{OLD} = 1.65V Max |
| I _{OHD} | Output Current (Note 3) | | | | −75 | mA | V _{OHD} = 3.85V Min |
| V _{OLP} | Quiet Output Maximum Dynamic V _{OL} | 5.0 | 0.5 | 0.8 | | V | Figure 1, Figure 2 (Note 5)(Note 6) |
| V _{OLV} | Quiet Output Minimum Dynamic V _{OL} | 5.0 | −0.5 | −0.8 | | V | Figure 1, Figure 2 (Note 5)(Note 6) |
| V _{OHP} | Maximum Overshoot | 5.0 | V _{OH} + 1.0 | V _{OH} + 1.5 | | V | Figure 1, Figure 2 (Note 4)(Note 6) |
| V _{OHV} | Minimum V _{CC} Droop | 5.0 | V _{OH} − 1.0 | V _{OH} − 1.8 | | V | Figure 1, Figure 2 (Note 4)(Note 6) |
| V _{IHD} | Minimum HIGH Dynamic Input Voltage Level | 5.0 | 1.7 | 2.0 | | V | (Note 4)(Note 7) |
| V _{ILD} | Maximum LOW Dynamic Input Voltage Level | 5.0 | 1.2 | 0.8 | | V | (Note 4)(Note 7) |

Note 2: All outputs loaded; thresholds associated with output under test.

Note 3: Maximum test duration 2.0 ms; one output loaded at a time.

Note 4: Worst case package.

DC Electrical Characteristics (Continued)

Note 5: Maximum number of outputs that can switch simultaneously is n . ($n - 1$) outputs are switched LOW and one output held LOW.

Note 6: Maximum number of outputs that can switch simultaneously is n . ($n - 1$) outputs are switched HIGH and one output held HIGH.

Note 7: Maximum number of data inputs (n) switching. ($n - 1$) inputs switching 0V to 3V Input under test switching 3V to threshold (V_{ILD}).

AC Electrical Characteristics

| Symbol | Parameter | V _{CC} (V) (Note 8) | T _A = +25°C C _L = 50 pF | | | T _A = -40°C to +85°C C _L = 50 pF | | Units |
|--------------------------------------|---|------------------------------------|--|------------|-------------|---|-------------|-------|
| | | | Min | Typ | Max | Min | Max | |
| t _{PLH} t _{PHL} | Propagation Delay Transparent Mode A _n to B _n or B _n to A _n | 5.0 | 3.8 3.5 | 5.9 5.5 | 8.3 7.9 | 3.0 2.6 | 9.0 8.5 | ns |
| t _{PLH} t _{PHL} | Propagation Delay LEBA _n , LEAB _n to A _n , B _n | 5.0 | 4.7 3.9 | 6.9 6.3 | 9.8 9.0 | 3.4 3.1 | 10.8 9.8 | ns |
| t _{PZH} t _{PZL} | Output Enable Time OEBA _n or OEAB _n to A _n or B _n CEBA _n or CEAB _n to A _n or B _n | 5.0 | 4.2 4.9 | 6.3 7.3 | 9.2 10.3 | 3.0 3.6 | 9.9 10.3 | ns |
| t _{PHZ} t _{PLZ} | Output Disable Time OEBA _n or OEAB _n to A _n or B _n CEBA _n or CEAB _n to A _n or B _n | 5.0 | 2.8 2.6 | 5.2 5.0 | 8.0 7.6 | 2.1 2.0 | 8.3 8.1 | ns |

Note 8: Voltage Range 5.0 is 5.0V ±0.5V.

AC Operating Requirements

| Symbol | Parameter | V _{CC} (V) (Note 9) | T _A = +25°C C _L = 50 pF | | T _A = -40°C to +85°C C _L = 50 pF | Units |
|----------------|---|------------------------------------|--|--------------------|---|-------|
| | | | Typ | Guaranteed Minimum | | |
| t _S | Setup Time, HIGH or LOW A _n or B _n to $\overline{\text{LEBA}}_n$ or $\overline{\text{LEAB}}_n$ | 5.0 | | 3.0 | 3.0 | ns |
| t _H | Hold Time, HIGH or LOW A _n or B _n to $\overline{\text{LEBA}}_n$ or $\overline{\text{LEAB}}_n$ | 5.0 | | 1.5 | 1.5 | ns |
| t _W | Latch Enable, B to A Pulse Width, LOW | 5.0 | | 4.0 | 4.0 | ns |

Note 9: Voltage Range 5.0 is 5.0V ±0.5V

Extended AC Electrical Characteristics

| Symbol | Parameter | $T_A = -40$ to $+85^{\circ}\text{C}$ $V_{CC} = \text{Com}$ $C_L = 50 \text{ pF}$ 16 Outputs Switching (Note 10) | | | $T_A = -40$ to $+85^{\circ}\text{C}$ $V_{CC} = \text{Com}$ $C_L = 250 \text{ pF}$ (Note 11) | | Units |
|-------------------------|--|---|-----|------|--|------|-------|
| | | Min | Typ | Max | Min | Max | |
| t_{PLH} | Propagation Delay | 4.5 | | 11.1 | 5.8 | 14.3 | ns |
| t_{PHL} | Transparent Mode A_n to B_n or B_n to A_n | 3.7 | | 9.6 | 5.1 | 13.4 | |
| t_{PLH} | Propagation Delay | 4.3 | | 11.3 | 6.2 | 16.3 | ns |
| t_{PHL} | $\overline{LE}B\overline{A}_n$, $\overline{LE}A\overline{B}_n$ to A_n , B_n | 3.7 | | 9.7 | 5.8 | 14.9 | |
| t_{PZH} | Output Enable Time | 4.0 | | 10.7 | (Note 12) | | ns |
| t_{PZL} | $\overline{OE}B\overline{A}_n$ or $\overline{OE}A\overline{B}_n$ to A_n or B_n $\overline{CE}B\overline{A}_n$ or $\overline{CE}A\overline{B}_n$ to A_n or B_n | 4.3 | | 11.3 | | | |
| t_{PHZ} | Output Disable Time | 3.0 | | 8.0 | (Note 13) | | ns |
| t_{PLZ} | $\overline{OE}B\overline{A}_n$ or $\overline{OE}A\overline{B}_n$ to A_n or B_n $\overline{CE}B\overline{A}_n$ or $\overline{CE}A\overline{B}_n$ to A_n or B_n | 2.8 | | 7.6 | | | |
| t_{OSHL} (Note 14) | Pin to Pin Skew HL Data to Output | | | 1.1 | | | ns |
| t_{OSLH} (Note 14) | Pin to Pin Skew LH Data to Output | | | 1.4 | | | ns |
| t_{OSHL} (Note 14) | Pin to Pin Skew Latch to Output | | | 2.6 | | | ns |
| t_{OSLH} (Note 14) | Pin to Pin Skew Latch to Output | | | 1.0 | | | ns |
| t_{OST} (Note 14) | Pin to Pin Skew Data to Output | | | 1.0 | | | ns |
| t_{OST} (Note 14) | Pin to Pin Skew Latch to Output | | | 2.2 | | | ns |

Note 10: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.).

Note 11: This specification is guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 12: 3-STATE delays are load dominated and have been excluded from the datasheet.

Note 13: The Output Disable Time is dominated by the RC network (500Ω, 250 pF) on the output and has been excluded from the datasheet.

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW (t_{OSHL}), LOW to HIGH (t_{OSLH}), or any combination switching LOW to HIGH and/or HIGH to LOW (t_{OST}).

Capacitance

| Symbol | Parameter | Typ | Units | Conditions |
|----------|-------------------------------|------|-------|------------------------|
| C_{IN} | Input Capacitance | 4.5 | pF | $V_{CC} = 5.0\text{V}$ |
| C_{PD} | Power Dissipation.Capacitance | 95.0 | pF | $V_{CC} = 5.0\text{V}$ |

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

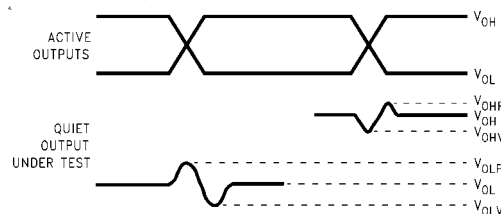
Hewlett Packard Model 8180A Word Generator

PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

1. Verify Test Fixture Loading: Standard Load 50 pF, 500Ω.
2. Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.



V_{OHV} and V_{OLP} are measured with respect to ground reference.

Input pulses have the following characteristics: $f = 1$ MHz, $t_r = 3$ ns, $t_f = 3$ ns, skew < 150 ps.

FIGURE 1. Quiet Output Noise Voltage Waveforms

5. Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
6. Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.

V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV} :

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the worst case transition for active and enable. Measure V_{OHP} and V_{OHV} on the quiet output during the worst case for active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD} :

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL} , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD} .
- Next decrease the input HIGH voltage level, V_{IH} , until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD} .
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability on the measurements.

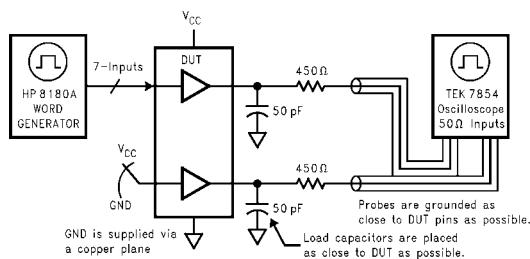
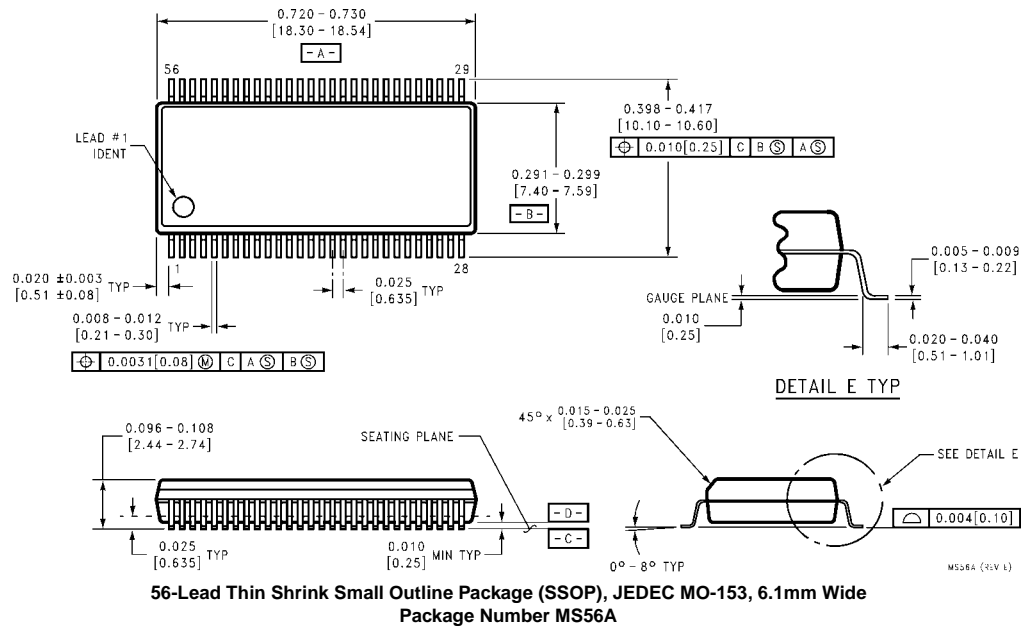
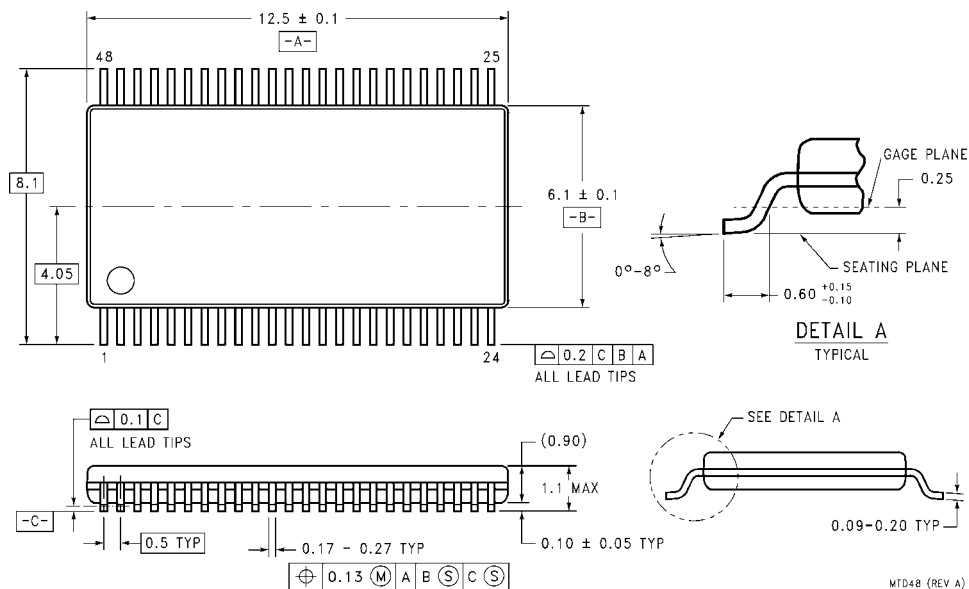


FIGURE 2. Simultaneous Switching Test Circuit

Physical Dimensions inches (millimeters) unless otherwise noted





**56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide
Package Number MTD56**

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